



# Certificate of Analysis

## IARM Fe2205-18

Stainless Steel Alloy 2205 / UNS S32205

### Certified Reference Material

#### Certified Values listed in wt.% with associated uncertainties

Al	<b>0.007 ± 0.005</b>	C	<b>0.018 ± 0.002</b>	Co	<b>0.104 ± 0.005</b>	Cr	<b>22.6 ± 0.1</b>
Cu	<b>0.208 ± 0.004</b>	Mn	<b>1.18 ± 0.02</b>	Mo	<b>3.20 ± 0.05</b>	N	<b>0.17 ± 0.02</b>
Nb	<b>0.011 ± 0.004</b>	Ni	<b>5.57 ± 0.09</b>	O	<b>0.004 ± 0.003</b>	P	<b>0.023 ± 0.003</b>
S	<b>0.0013 ± 0.0009</b>	Si	<b>0.46 ± 0.01</b>	Sn	<b>0.006 ± 0.002</b>	Ti	<b>0.003 ± 0.003</b>
V	<b>0.063 ± 0.004</b>	W	<b>0.024 ± 0.004</b>				

#### Indicative Values listed in ppm

As (30)	B (20)	Bi (<1)	Ca (20)	Cd (<1)	H (10)	Mg (<10)
Pb (<30)	Sb (10)	Se (<10)	Ta (200)	Zn (<50)	Zr (<50)	

#### Description and Intended Use

This CRM may come in the form of a solid disk, chips, or powder. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

#### Instructions for Use

1. The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface.
2. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams.
3. The material should be stored in a cool, dry location when not in use.
4. **Chips are not certified for Oxygen analysis.**



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	As	B	Bi	C	Ca	Cd	Co	Cr	Cu	Fe	H	Mg	Mn	Mo	N
1	0.0001567	0.00033	0.00113	<0.0001	0.0109	0.00132	<0.0001	0.093467	22.15	0.1992	66.628	0.00131	0.000387	1.115	3.078	0.117
2	0.00156	0.0036	0.0016		0.0134	0.0016		0.095	22.435	0.20238	67.04	0.0002	<0.001	1.132	3.08	0.174
3	0.0031	0.0039	0.0016		0.0178	0.0026		0.0951	22.50794	0.204		0.00182	<0.0001	1.151	3.175583	0.174
4	0.004	0.00407	0.0035		0.018	0.003		0.1013	22.5259	0.205			<0.0005	1.162	3.1865	0.1751
5	0.004	<0.001	0.0044		0.0187	<0.001		0.1057	22.546	0.2056				1.1648	3.18667	0.1763
6	0.0045	<0.005	<0.005		0.019	<0.005		0.105967	22.6	0.20567				1.176	3.2	0.177
7	0.0059				0.0192			0.106	22.609	0.20668				1.176	3.20424	0.177
8	0.006				0.0192			0.107	22.63	0.209				1.19667	3.22	
9	0.02				0.02			0.108	22.6647	0.21				1.20205	3.222	
10	0.021				0.022			0.111	22.7533	0.21				1.21	3.28	
11					0.022033			0.118	22.82	0.211				1.243	3.284	
12									22.933	0.227					3.334	
13																
14																
15																
Mean	0.007	0.003	0.002		0.018	0.002		0.104	22.6	0.208	66.8	0.001		1.18	3.2	0.17
STDV.	0.007	0.002	0.001		0.003	0.0008		0.007	0.2	0.007	0.3	0.0008		0.04	0.08	0.02
<b>Certified</b>	<b>0.007</b>	<b>(0.003)</b>	<b>(0.002)</b>	<b>(&lt;0.0001)</b>	<b>0.018</b>	<b>(0.002)</b>	<b>(&lt;0.0001)</b>	<b>0.104</b>	<b>22.6</b>	<b>0.208</b>	<b>(66.8)</b>	<b>(0.001)</b>	<b>(&lt;0.001)</b>	<b>1.18</b>	<b>3.20</b>	<b>0.17</b>
$U_{CRM}$	0.005	I,D,O	I,A	I,D	I	C,G,O	I,D	I	I,D,G,X,O	I,D,G,X,O	I,D,G,X,O	I,X	F	I,D	I,D,G,X,O	C,F
Methods																

	Nb	Ni	O	P	Pb	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr
1	0.0013267	5.454	0.0024	0.01644	0.0002	0.0004	0.000056	0.0006	0.428	0.002	0.0000213	0.00022	0.05511	0.012	0.000026	0.0000173
2	0.0042	5.4767	0.0031	0.019	<0.001	0.000667	0.000706	<0.001	0.432	0.005	0.031	0.001	0.057067	0.0178	0.0000925	0.003
3	0.008	5.483	0.0032	0.02	<0.0030	0.0007	0.001	<0.0001	0.44	0.005	0.038	0.00143	0.0585	0.022	<0.001	<0.0010
4	0.01152	5.4831	0.003633	0.021		0.001	0.0015	0.444	0.005	<0.0010	0.002	0.0606	0.022467	<0.0005	<0.002	
5	0.012	5.5412	0.00381	0.0212		0.001	<0.001	0.449	0.00504	<0.0010	0.002	0.0606	0.023	<0.0010	<0.005	
6	0.013	5.5469	0.004	0.0213		0.001		0.45	0.0085	<0.002	0.002	0.06087	0.026433			
7	0.015	5.548	0.0106	0.0215		0.0012		0.454	0.01	<0.005	0.004	0.061	0.02777			
8	0.0153	5.57		0.024		0.0016		0.469			0.0107	0.061	0.0278			
9	0.018	5.577		0.025		0.0043		0.471				0.061	0.028			
10		5.671		0.025				0.4831				0.067				
11		5.901		0.03				0.4856				0.075				
12												0.076				
13																
14																
15																
Mean	0.011	5.57	0.004	0.023		0.001	0.001	0.46	0.006	0.02	0.003	0.063	0.024	0.0001	0.002	
STDV.	0.005	0.1	0.003	0.004		0.001	0.0006	0.02	0.003	0.02	0.003	0.007	0.006	0.00005	0.002	
<b>Certified</b>	<b>0.011</b>	<b>5.57</b>	<b>0.004</b>	<b>0.023</b>	<b>(&lt;0.003)</b>	<b>0.001</b>	<b>(0.001)</b>	<b>(&lt;0.001)</b>	<b>0.46</b>	<b>0.006</b>	<b>(0.02)</b>	<b>0.003</b>	<b>0.063</b>	<b>0.024</b>	<b>(&lt;0.005)</b>	<b>(&lt;0.005)</b>
$U_{CRM}$	0.004	0.09	0.003	0.003		0.001	C,G,O	I,A	A,I	I,D,G,X,O	I,A,O	I,D	I,D,O	I,D,G,X,O	I,D	I,D
Methods	I,D,X,O	I,D,G,X,O	C,F	I,D,G,X,O	I,A											

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

### Certification Laboratories

Connecticut Metallurgical Inc  
IMR Test Labs  
EAG Laboratories  
Luvak Laboratories Inc.  
New Hampshire Materials Lab

East Hartford, CT  
Lansing, NY  
Liverpool, NY  
Boylston, MA  
Somersworth, NH

Dirats Laboratories  
VHG Labs  
Laboratory Testing, Inc.  
Massachusetts Materials Research Inc.

Westfield, MA  
Manchester, NH  
Hatfield, PA  
West Boylston, MA

Certification laboratories have demonstrated performance and traceability by utilizing test methods under the scope of ISO 17025 or have shown competence through a proficiency testing program. Some of the specific SRMs used in the analysis of the material covered by this certificate are:

NIST 101G

Nist 3100 Series

NIST 345A

NIST 361

NIST 363

NIST 1155

### Homogeneity and Uncertainty

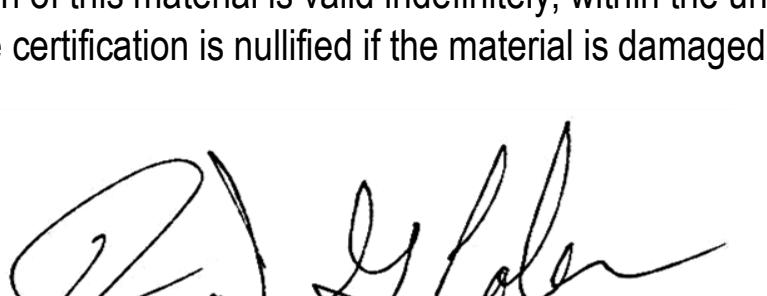
"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where  $N_{prod}$  is the number of units produced and  $N_{min}$  is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity ( $U_{hom}$ ). Uncertainty of the material is calculated by equation 2, where  $H=U_{hom}$ , S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

### Expiration

The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.



David Coler, General Manager

Analytical Reference Materials International

